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FormFactor Ships 125th DRAM Wafer Probe Card with Advanced TRE™ Technology
Advanced TRE extends the life of existing testers and reduces additional capital expenditures

LIVERMORE, Calif. – December 29, 2009 – FormFactor, Inc. (Nasdaq: FORM) today announced that it has reached a milestone with the shipment of the 125th wafer probe card incorporating the company's proprietary advanced TRE™ technology. Advanced TRE technology enables FormFactor's probe cards to make more efficient use of tester channels on test equipment to multiply the number of devices that can be tested simultaneously on a wafer with existing resources. As a result, probe cards incorporating FormFactor's advanced TRE technology can extend the life of existing test equipment, allowing semiconductor manufacturers to defer the cost of purchasing new equipment while still addressing increases in test capacity or new test requirements.

FormFactor has shipped probe cards with advanced TRE technology to several of the top DRAM manufacturers, and are currently being used to test DDR2 and DDR3 DRAM devices with densities ranging from 512MB to 2GB. The production-proven technology brings a new degree of intelligence to FormFactor wafer probe cards through the integration of application specific ICs. With this proprietary capability, FormFactor's advanced TRE enabled probe cards take wafer test parallelism to the next level.

"As DRAM manufacturers drive to smaller technology nodes to lower their production costs, the number of DRAM devices being produced and tested per wafer continues to rise. As a result, our customers need innovative solutions to lower their test costs while maintaining test quality," stated Stefan Zschiegner, senior vice president and general manager of FormFactor's DRAM Product Business Group. "By enabling higher levels of test parallelism, FormFactor's wafer probe cards with advanced TRE technology can lower the cost of test by up to 30 percent or more, as well as help customers avoid millions of dollars in capital expenditure by extending the life of their existing testers—all without compromising on test coverage and yield."

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Forward-Looking Statements

Statements in this press release that are not strictly historical in nature are forward-looking statements within the meaning of the federal securities laws, including statements regarding future growth. These forward-looking statements are based on current information and expectations that are inherently subject to change and involve a number of risks and uncertainties. Actual events or results might differ materially from those in any forward-looking statement due to various factors, including, but not limited to: the Company's ability to implement its advanced TRE technology to enable its probe cards to multiply the number of devices that can be tested simultaneously on a wafer with existing resources; whether the Company's probe cards implementing advanced TRE technology allow semiconductor manufacturers to defer the cost of purchasing new equipment while still addressing increases in test capacity or new test requirements; whether the Company's advanced TRE probe cards can lower the cost of test by up to 30 percent or more without compromising on test coverage and yield; and the Company's ability to implement its DC-Boost technology in its advanced TRE probe cards to enable semiconductor manufacturers to achieve increased test reading reliability and realize improved yields. Additional information concerning factors that could cause actual events or results to differ materially from those in any forward-looking statement is contained in the company's Form 10-K for the fiscal year ended December 27, 2008 and the company's Form 10-Q for the fiscal quarter ended September 26, 2009, both as filed with the Securities and Exchange Commission ("SEC"), and subsequent SEC filings. Copies of the company's SEC filings are available at <http://investors.formfactor.com/edgar.cfm>. The company assumes no obligation to update the information in this press release, to revise any forward-looking statements or to update the reasons actual results could differ materially from those anticipated in forward-looking statements.

About FormFactor

Founded in 1993, FormFactor, Inc. (Nasdaq: FORM) is the leader in advanced wafer probe cards, which are used by semiconductor manufacturers to electrically test ICs. The company's wafer sort, burn-in and device performance testing products move IC testing upstream from post-packaging to the wafer level, enabling semiconductor manufacturers to lower their overall production costs, improve yields, and bring next-generation devices to market. FormFactor is headquartered in Livermore, California with operations in Europe, Asia and North America. For more information, visit the company's web site at www.formfactor.com.

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